

#### RN2112FT, RN2113FT

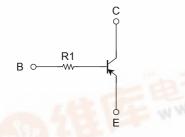
TOSHIBA Transistor Silicon PNP Epitaxial Type (PCT process) (Bias Resistor built-in Transistor)

# **RN2112FT, RN2113FT**

Switching, Inverter Circuit, Interface Circuit and Driver Circuit Applications.

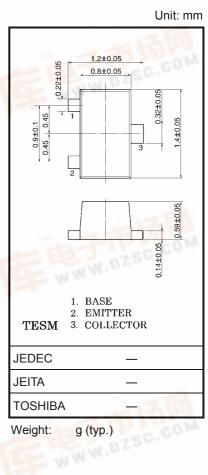
- High-density mount is possible because of devices housed in very thin TESM packages.
- Incorporating a bias resistor into a transistor reduces parts count. Reducing the parts count enable the manufacture of ever more compact equipment and save assembly cost.
- Wide range of resistor values are available to use in various circuit designs.
- Complementary to RN1112FT, RN1113FT

#### **Equivalent Circuit and Bias Resistor Values**



#### Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Collector-base voltage	V <sub>CBO</sub>	-50	V
Collector-emitter voltage	V <sub>CEO</sub>	-50	V
Emitter-base voltage	VEBO	-5	V
Collector current	IC	-100	mA
Collector power dissipation	P <sub>C</sub>	100	mW
Junction temperature	Tj	150	°C
Storage temperature range	T <sub>stg</sub>	-55~150	°C

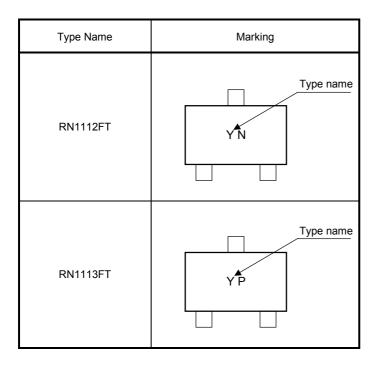


Weight:



### Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	$V_{CB}=-50~V,~I_{E}=0$			-100	nA
Emitter cut-off curren	t	I <sub>EBO</sub>	$V_{EB} = -5 \text{ V}, \text{ I}_{C} = 0$	_		-100	nA
DC current gain h <sub>FE</sub>		h <sub>FE</sub>	$V_{CE} = -5 \text{ V}, \text{ I}_{C} = -1 \text{ mA}$	120	_	400	
Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	$I_{C} = -5 \text{ mA}, I_{B} = -0.25 \text{ mA}$	_	-0.1	-0.3	V
Transition frequency		f <sub>T</sub>	$V_{CE} = -10 \text{ V}, \text{ I}_{C} = -5 \text{ mA}$	_	200	_	MHz
Collector output capacitance		C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, \text{ I}_{E} = 0, \text{ f} = 1 \text{ MHz}$	_	3	6	pF
Input resistor	RN2112FT	R1		15.4	22	28.6	kΩ
	RN2113FT		—	32.9	47	61.1	



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